Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	91	(prevent$4 or stop$4) near10 reset near10 float$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
L2	74	1 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
L3	2449526	(integrated adj circuit$1) or chip$1 or memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 13:04
L4	34	2 and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 13:04
S1	4613	reset$4 near10 (circuit$1 or chip$1 or device$1) near10 external$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:17
S2	62085	"365"/$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:27
S3	639	S1 and S2 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
S4	1710295	test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:33
S5	349	S3 and S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:28

S6	535	reset$3 near10 (voltage$1 or potential$1) near10 test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:39
S7	89	S2 and S6 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:40
S14	765	reset$3 near20 (voltage$1 or potential$1) near20 test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S15	128	S2 and S14 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S16	39	S15 not S7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:40
S17	68	reset$3 near20 bias near20 test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:13
S18	808	reset$3 near20 (voltage$1 or potential$1 or bias) near20 test$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S19	657	S18 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:15
S20	529	S19 not S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:15
S21	133954	reset$4 near10 (circuit$1 or chip$1 or device$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:19

S22	336	S20 and S21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:17
S23	299568	test$4 near10 (circuit$1 or chip$1 or device$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:19
S24	296	S22 and S23	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:31
S27	2447534	(integrated adj circuit$1) or chip$1 or memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:56